

256K (32K x 8) Static RAM

Features

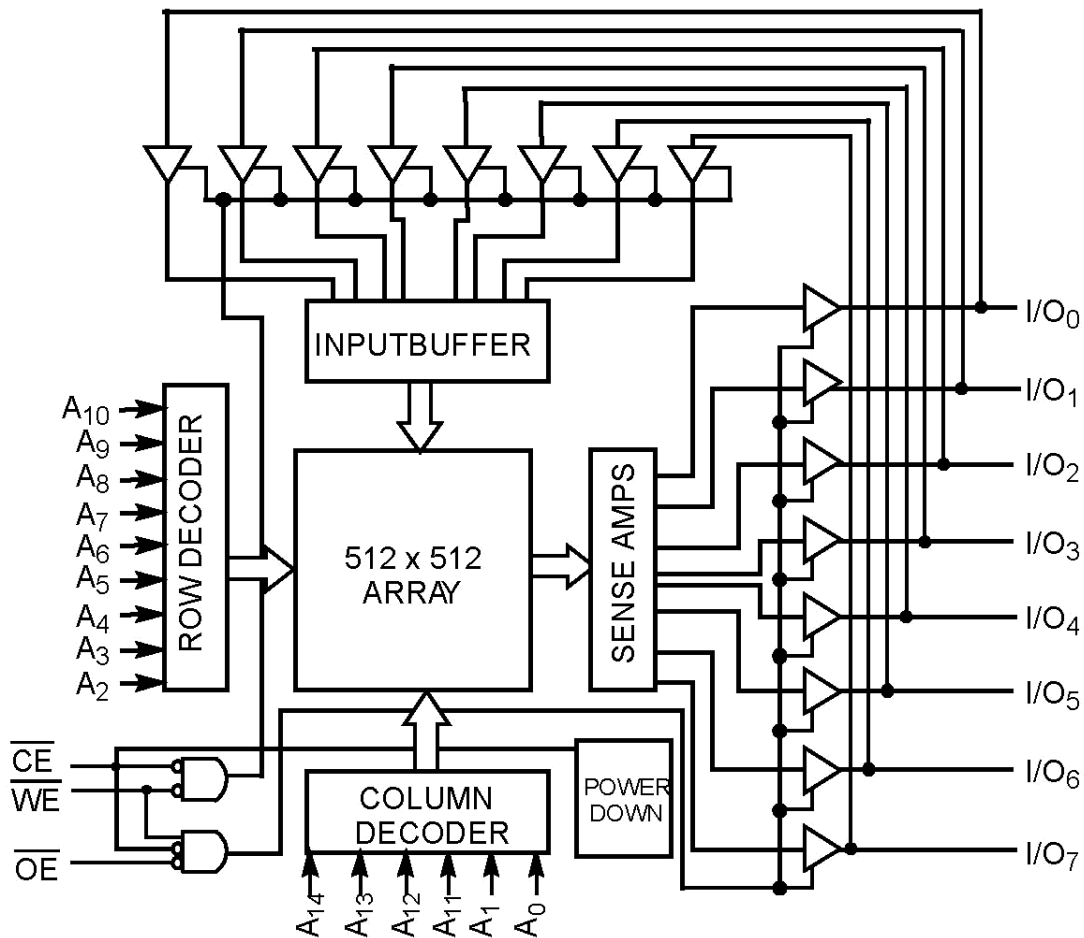
- Temperature Ranges
 - Commercial: 0 to 70
 - Industrial: -40 to 85
 - Automotive: -40 to 125
- High speed: 55ns and 70 ns
- Voltage range : 4.5V –5.5V operation
- Low active power (70ns, LL version, Com'l and Ind'l) -275mW (max)
- Low standby power (70ns, LL Version, Com'l and Ind'l) -28 μ W (max.)
- Easy memory expansion with \overline{CS} and \overline{OE} features
- TTL – compatible inputs and outputs
- Automatic power-down when deselected
- CMOS for optimum speed/power
- Package available in a standard 450-mil-wide (300-mil body width) 28-lead narrow SOIC, 28-lead TSOP-1, 28-lead reverse TSOP-1, and 600-mial 28-lead PDIP packages.

Functional Description [1]

The CY62256 is a high-performance CMOS static RAM organized as 32K words by 8 bits. Easy memory expansion is provided by an active LOW output enable (\overline{CE}) and active LOW output enable (\overline{OE}) and three-state drives. This device has an automatic power-down feature, reducing the power consumption by 99.9% when deselected.

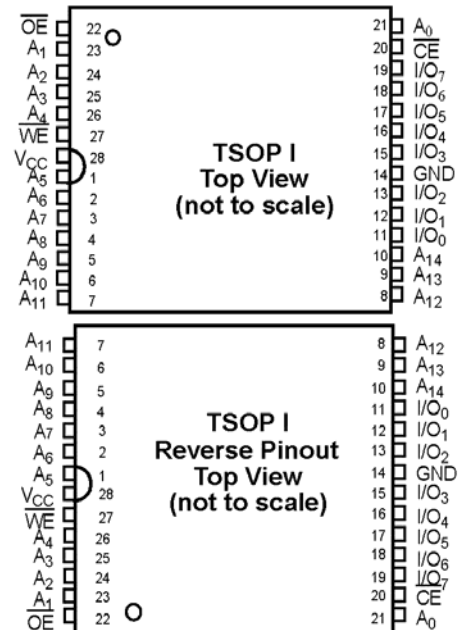
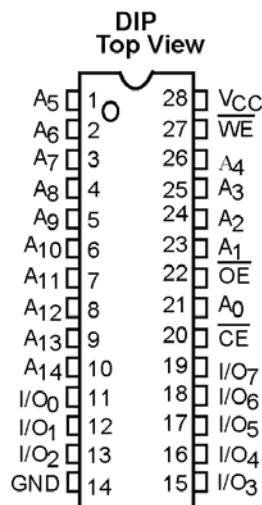
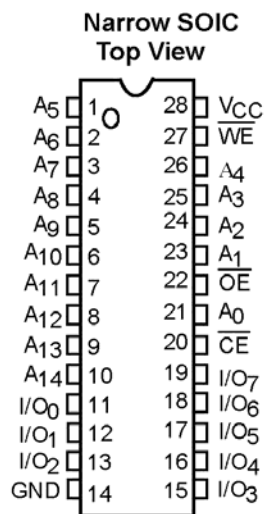
An active Low write enable signal (\overline{WE}) controls the writing/reading operation of the memory. When \overline{CE} and \overline{WE} inputs are both LOW, data on the eight data input/output pins (I/O_0 through I/O_7) is written into the memory location addressed by the address present on the address pins (A_0 through A_{14}). Reading the device is accomplished by selecting the device and enabling the outputs, \overline{CE} and \overline{OE} active LOW while \overline{WE} remains inactive or HIGH. Under these conditions, the contents of the location addressed by the information on address pins are present on the eight data input/output pins. The input/output pins remain in a high-impedance state unless the chip is selected, outputs are enabled, and write enable (\overline{WE}) is HIGH.

Logic Block Diagram



Product Portfolio

| Product | | Vcc Range (V) | | | Speed (ns) | Power Dissipation | | | |
|-----------|---------------|---------------|---------|------|------------|---------------------------------|------|--------------------------------------|------|
| | | Min. | Typ.[2] | Max. | | Operating, I _{cc} (mA) | | Standby, I _{SB2} (μ A) | |
| | | | | | | Typ.[2] | Max. | Typ.[2] | Max. |
| CY62256 | Commercial | 4.5 | 5.0 | 5.5 | 70 | 28 | 55 | 1 | 5 |
| CY62256L | Com'l / Ind'l | | | | 55/70 | 25 | 50 | 2 | 50 |
| CY62256LL | Commercial | | | | 70 | 25 | 50 | 0.1 | 5 |
| CY62256LL | Industrial | | | | 55/70 | 25 | 50 | 0.1 | 10 |
| CY62256LL | Automotive | | | | 55 | 25 | 50 | 0.1 | 15 |

Pin Configurations

Pin Definitions

| Pin Number | Type | Description |
|---------------|---------------|--|
| 1-10,21,23-26 | Input | A ₀ -A ₁₄ . Address Inputs |
| 11-13,15-19, | Input/Output | I/O ₀ -I/O ₇ . Data lines. Used as input or output lines depending on operation |
| 27 | Input/Control | \overline{WE} . When selected Low, a WRITE is conducted. When selected HIGH, a READ is conducted |
| 20 | Input/Control | \overline{CE} . When LOW, selects the chip. When HIGH, deselects the chip |
| 22 | Input/Control | \overline{OE} . Output Enable. Controls the direction of the I/O pins. When LOW, the I/O pins behave as outputs. When deasserted HIGH, I/O pins are three-stated, and act as input data pins |
| 14 | Ground | GND. Ground for the device |
| 28 | Power Supply | Vcc. Power supply for the device |

Notes:

2. Typical specifications are the mean values measured over a large sample size across normal production process variations and are taken at nominal conditions ($T_A = 25^\circ\text{C}$, Vcc), Parameters are guaranteed by design and characterization, and not 100% tested.

Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

| | |
|--|--------------------|
| Storage Temperature..... | -65 to +150 |
| Ambient Temperature with Power Applied..... | -55 to +125 |
| Supply Voltage to Ground Potential (Pin 28 to Pin 14)..... | -0.5V to +7.0V |
| DC Voltage Applied to Outputs In High-Z State ^[3] | -0.5V to Vcc +0.5V |
| DC Input Voltage ^[3] | -0.5V to Vcc +0.5V |

Output Current into Outputs (LOW).....20mA
 Static Discharge Voltage.....>2001V
 (per MIL-STD-883, Method 3015)

Latch-up Current.....>200mA

Operating Range

| Range | Ambient Temperature(T _A) ^[4] | Vcc |
|------------|---|----------|
| Commercial | 0 to +70 | 5V ± 10% |
| Industrial | -40 to +80 | 5V ± 10% |
| Automotive | -40 to +125 | 5V ± 10% |

Electrical Characteristics Over the Operating Range

| Parameter | Description | Test Conditions | CY62256-55 | | | CY62256-70 | | | Unit |
|------------------|---|--|------------|---------|-----------------------|------------|---------|-----------------------|------|
| | | | Min. | Typ.[2] | Max. | Min. | Typ.[2] | Max. | |
| V _{OH} | Output HIGH Voltage | V _{CC} =Min., I _{OH} =-1.0mA | 2.4 | | | 2.4 | | | V |
| V _{OL} | Output LOW Voltage | V _{CC} =Min., I _{OL} =2.1mA | | | 0.4 | | | 0.4 | V |
| V _{IH} | Input HIGH Voltage | | 2.2 | | V _{CC} +0.5V | 2.2 | | V _{CC} +0.5V | V |
| V _{IL} | Input LOW Voltage | | -0.5 | | 0.8 | -0.5 | | 0.8 | V |
| I _{LX} | Output Leakage Current | GND ≤ V _I ≤ V _{CC} | -0.5 | | +0.5 | -0.5 | | +0.5 | μA |
| I _{OZ} | Output Leakage Current | GND ≤ V _O ≤ V _{CC} , Output Disabled | -0.5 | | +0.5 | -0.5 | | +0.5 | μA |
| I _{CC} | V _{CC} Operating Supply Current | V _{CC} =Max., I _{OUT} =0mA, f=f _{MAX} = 1/t _{RC} | | 28 | 55 | | 28 | 55 | mA |
| | | L | | 25 | 50 | | 25 | 50 | mA |
| | | LL | | 25 | 50 | | 25 | 50 | mA |
| I _{SB1} | Automatic CE Power-down Current-TTL Inputs | Max. V _{CC} , $\overline{CE} \geq V_{IH}$, V _{IH} ≥ V _{IH} or V _{IN} ≤ V _{IL} , f=f _{MAX} | | 0.5 | 2 | | 0.5 | 2 | mA |
| | | L | | 0.4 | 0.6 | | 0.4 | 0.6 | mA |
| | | LL | | 0.3 | 0.5 | | 0.3 | 0.5 | mA |
| I _{SB2} | Automatic CE Power-down Current-CMOS Inputs | Max. V _{CC} , $\overline{CE} \geq V_{CC}-0.3V$, V _{IN} ≥ V _{CC} -0.3V, or V _{IN} ≤ 0.3V, f=0 | | 1 | 5 | | 1 | 5 | mA |
| | | L | | 2 | 50 | | 2 | 50 | μA |
| | | LL | | 0.1 | 5 | | 0.1 | 5 | μA |
| | | LL-Ind'l | | 0.1 | 10 | | 0.1 | 10 | μA |
| | | LL-Auto | | 0.1 | 15 | | | | μA |

Capacitance ^[5]

| Parameter | Description | Test Conditions | Max. | Unit |
|------------------|--------------------|-----------------------------|------|------|
| C _{IN} | Input Capacitance | T _A =25 , f=1MHz | 6 | pF |
| C _{OUT} | Output Capacitance | V _{CC} =5.0V | 8 | pF |

Notes:

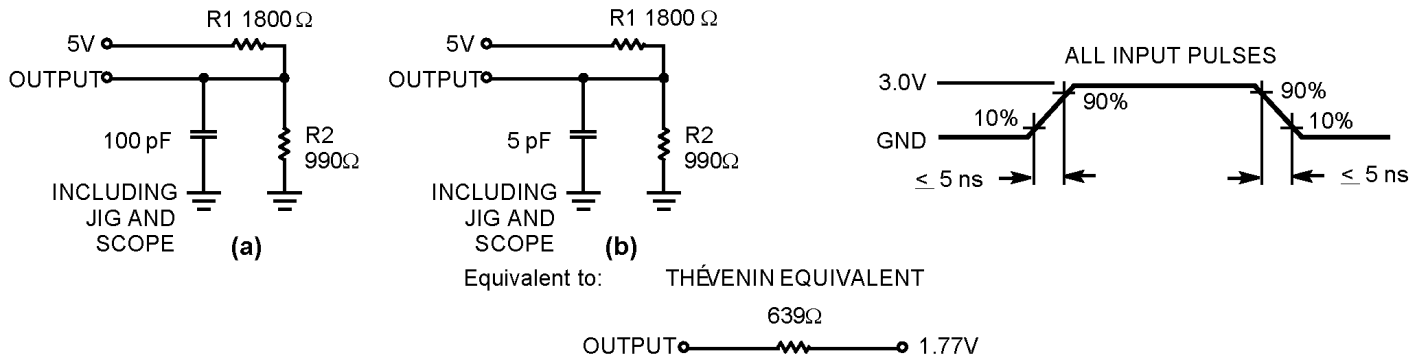
3. V_{IL} (min.)=-2.0V for pulse durations of less than 20ns.

4. T_A is the "Instant-On" case temperature.

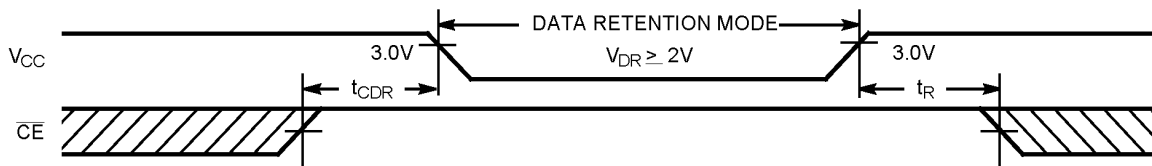
5. Tested initially and after any design or process changes that may affect these parameters.

Thermal Resistance

| Description | Test Conditions | Symbol | DIP | SOIC | TSOP | RTSOP | Unit |
|---|---|--------|-------|-------|-------|-------|------|
| Thermal Resistance (Junction to Ambient) ^[5] | Still Air, soldered on a 4.25 x 1.125 Inch, 4-layer printed circuit board | ⊕JA | 75.61 | 76.56 | 93.89 | 93.89 | /W |
| Thermal Resistance (Junction to Case) ^[5] | | ⊕JC | 43.12 | 36.07 | 24.64 | 24.64 | /W |

AC Test Loads and Waveforms

Data Retention Characteristics

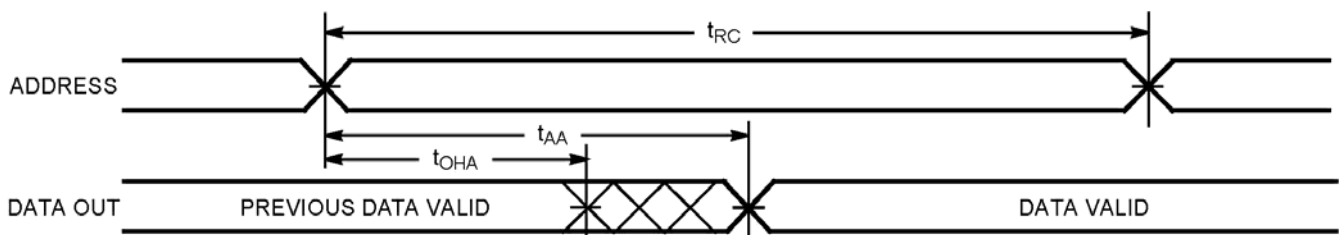
| Parameter | Description | Conditions[5] | Min. | Typ.[2] | Max. | Unit |
|----------------------|--------------------------------------|---------------|--|---------|------|------|
| V _{DR} | V _{CC} for Data Retention | | 2.0 | | | V |
| I _{CCDR} | Data Retention Current | L | V _{CC} =3.0V, $\overline{CE} \geq V_{CC}-0.3V$, V _{IN} ≥ V _{CC} - 0.3V, or V _{IN} ≤ 0.3V | 2 | 50 | μA |
| | | LL | | 0.1 | 5 | μA |
| | | LL-Ind'l | | 0.1 | 10 | μA |
| | | LL-Auto | | 0.1 | 10 | μA |
| t _{CDR} [5] | Chip Deselect to Data Retention Time | | 0 | | | ns |
| t _R [5] | Operation Recovery Time | | t _{RC} | | | ns |

Data Retention Waveform

Notes:

6. No input may exceed V_{CC} + 0.5.

Switching Characteristics Over the Operating Range ^[7]

| Parameter | Description | CY62256-55 | | CY62256-70 | | Unit |
|---------------------------------------|---|------------|------|------------|------|------|
| | | Min. | Max. | Min. | Max. | |
| Read Cycle | | | | | | |
| t_{RC} | Read Cycle Time | 55 | | 70 | | ns |
| t_{AA} | Address to Data Valid | | 55 | | 70 | ns |
| t_{OHA} | Data Hold from Address Change | 5 | | 5 | | ns |
| t_{ACE} | \overline{CE} LOW to Data valid | | 55 | | 70 | ns |
| t_{DOE} | \overline{OE} LOW to Data valid | | 25 | | 35 | ns |
| t_{LZOE} | \overline{OE} LOW to Low-Z ^[8] | 5 | | 5 | | ns |
| t_{HZOE} | \overline{OE} HIGH to High-Z ^[8,9] | | 20 | | 25 | ns |
| t_{LZOE} | \overline{OE} LOW to LOW-Z ^[8] | 5 | | 5 | | ns |
| t_{HZCE} | \overline{OE} LOW to LOW-Z ^[8,9] | | 20 | | 25 | ns |
| t_{PU} | \overline{CE} LOW to Power-up | 0 | | 0 | | ns |
| t_{PD} | \overline{CE} HIGH to Power-down | | 55 | | 70 | ns |
| Write Cycle ^[10,11] | | | | | | |
| t_{WC} | Write Cycle Time | 55 | | 70 | | ns |
| t_{SCE} | \overline{CE} LOW to Write End | 45 | | 60 | | ns |
| t_{AW} | Address Set-up to Write End | 45 | | 60 | | ns |
| t_{HA} | Address Hold from Write End | 0 | | 0 | | ns |
| t_{SA} | Address Set-up to Write Start | 0 | | 0 | | ns |
| t_{PWE} | \overline{WE} Pulse Width | 40 | | 50 | | ns |
| t_{SD} | Data Set-up to write End | 25 | | 30 | | ns |
| t_{HD} | Data Hold from Write End | 0 | | 0 | | ns |
| t_{HZWE} | \overline{WE} LOW to High-Z ^[8,9] | | 20 | | 25 | ns |
| t_{LZWE} | \overline{WE} HIGH to Low-Z ^[8] | 5 | | 5 | | ns |

Switching Waveforms
Read Cycle NO. 1 ^[12,13]

Notes:

7. Test conditions assume signal transition time of 5 ns or less, timing reference level is of 1.5V, input pulse levels of 0 to 3V, and output loading of the specified I_{OL}/I_{OH} and 100-pF load capacitance.

8. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZOE} , and t_{HZOE} is less than t_{HZCE} , and t_{LZWE} for any given device.

9. t_{HZOE} , t_{HZCE} , and t_{HZWE} are specified with $C_L=5pF$ as in (b) of AC Test Loads. Transition is measured $\pm 500mV$ from steady-state voltage.

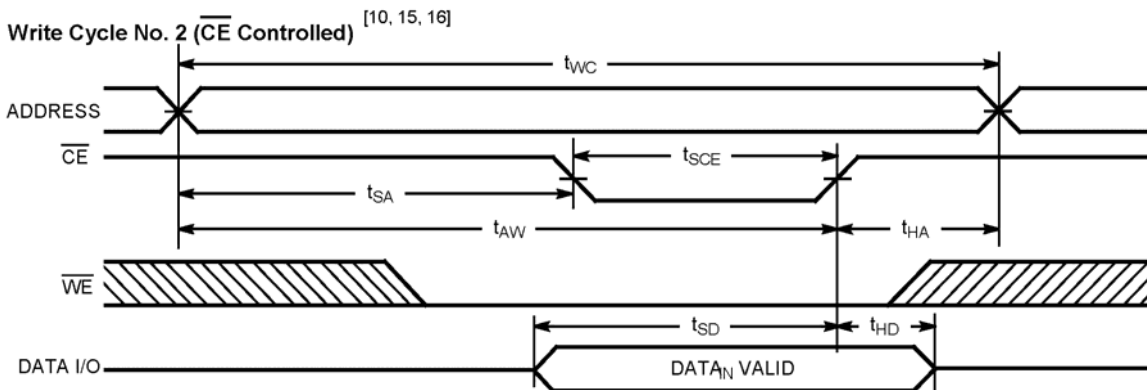
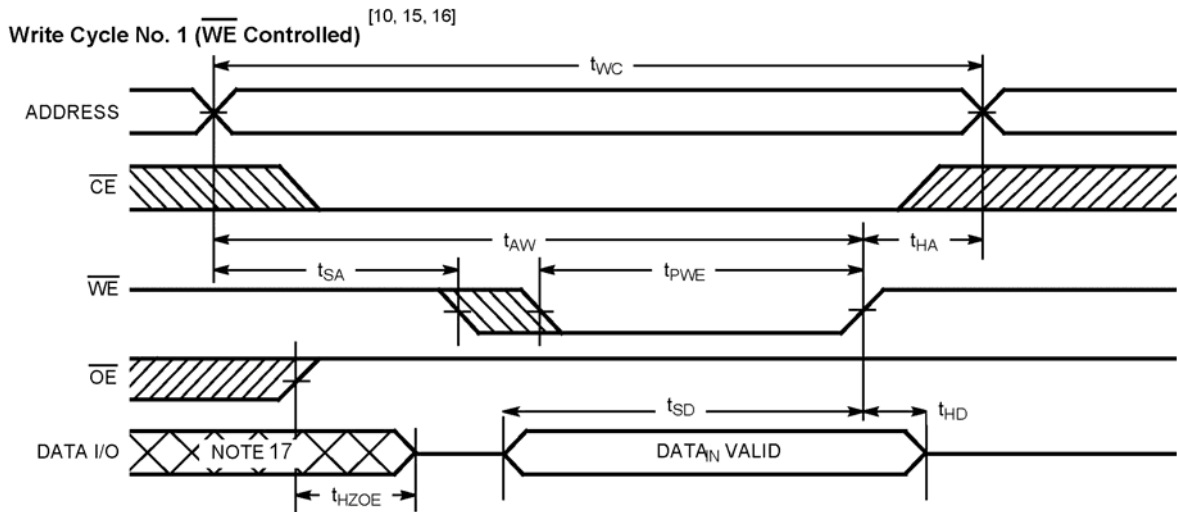
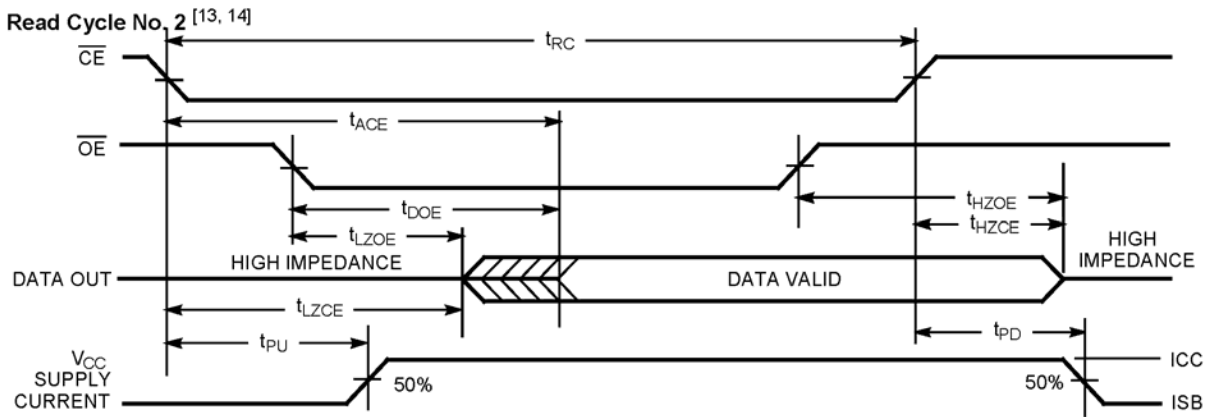
10. The internal Write time of the memory is defined by the overlap of \overline{CE} LOW and \overline{WE} LOW. Both signals must be Low to initiate a Write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the Write.

11. The minimum Write cycle time for Write cycle #3 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}

12. Device is continuously selected. \overline{OE} , $\overline{CE}=V_{IL}$.

13. \overline{WE} is HIGH for Read cycle.

Switching Waveforms (continued)

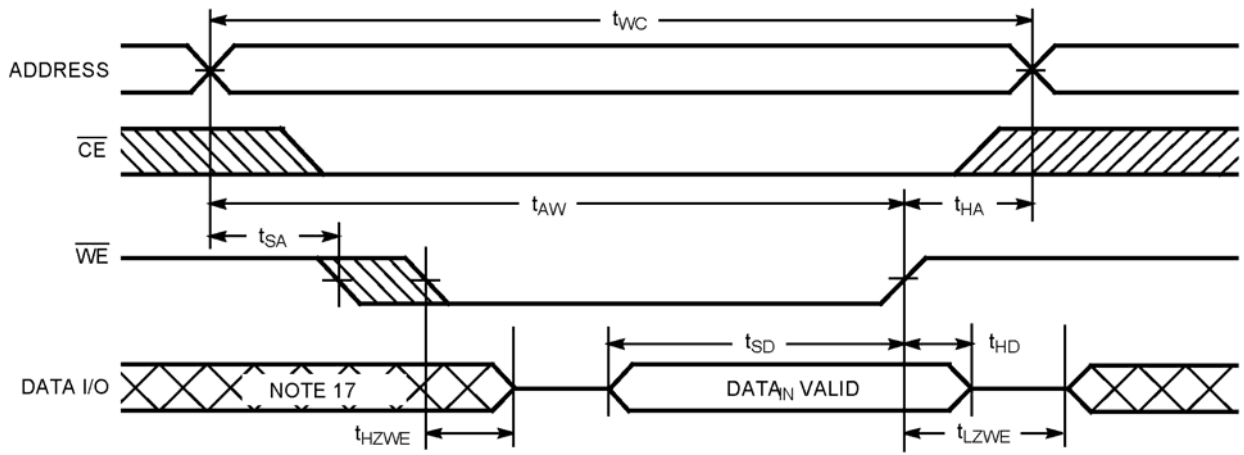


Notes:

- 14. Address valid prior to or coincident with \overline{CE} transition LOW.
- 15. Data I/O is high impedance if $\overline{OE} = V_{IH}$.
- 16. If \overline{CE} goes HIGH simultaneously with \overline{WE} HIGH, the output remains in a high-impedance state.
- 17. During this period, the I/Os are in output state and input signals should not be applied.

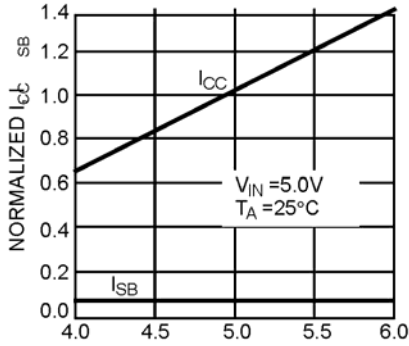
Switching Waveforms (continued)

Write Cycle No. 3 (\overline{WE} Controlled, \overline{OE} LOW) [11, 16]

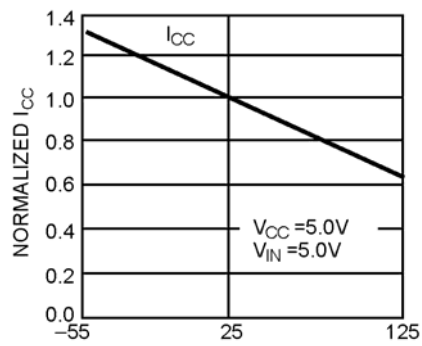


Typical DC and AC Characteristics

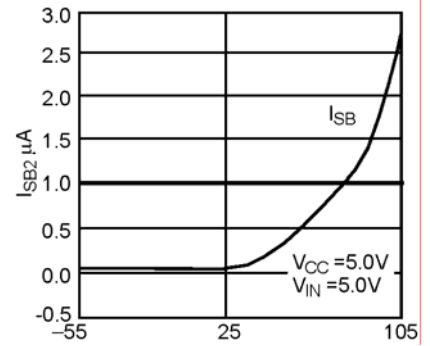
**NORMALIZED SUPPLY CURRENT
Vs. SUPPLY VOLTAGE**



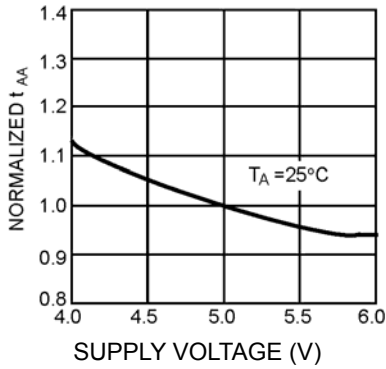
**NORMALIZED SUPPLY CURRENT
Vs. AMBIENT TEMPERATURE**



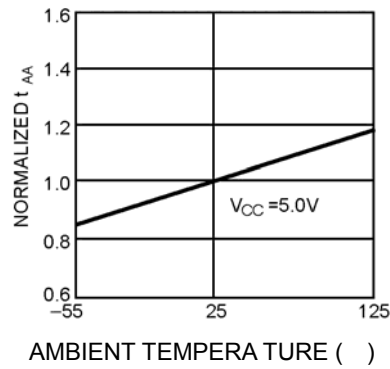
**STANDBY CURRENT
Vs. AMBIENT TEMPERATURE**



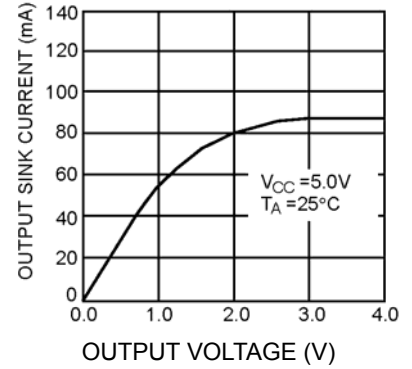
**NORMALIZED ACCESS TIME
Vs. SUPPLY VOLTAGE**



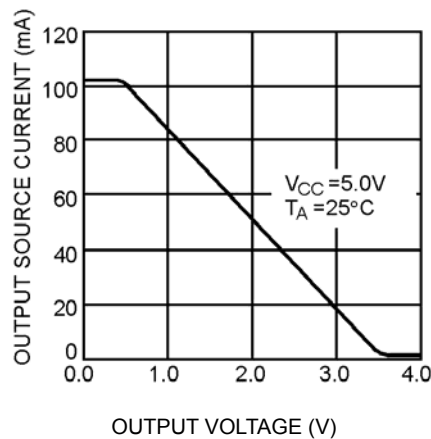
**NORMALIZED ACCESS TIME
Vs. AMBIENT TEMPERATURE**

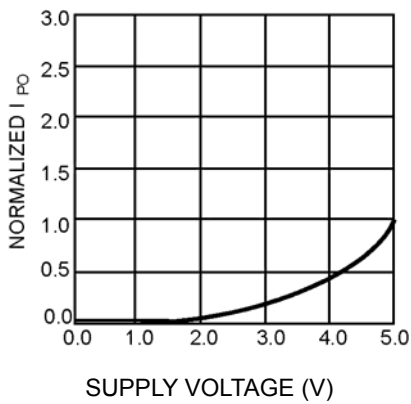
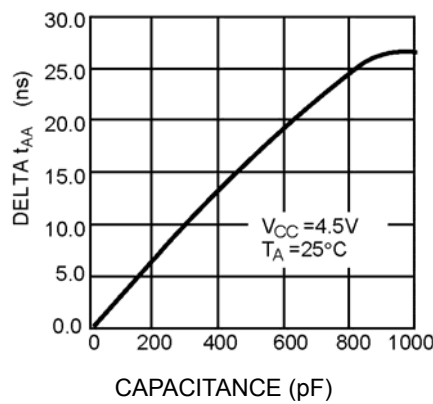
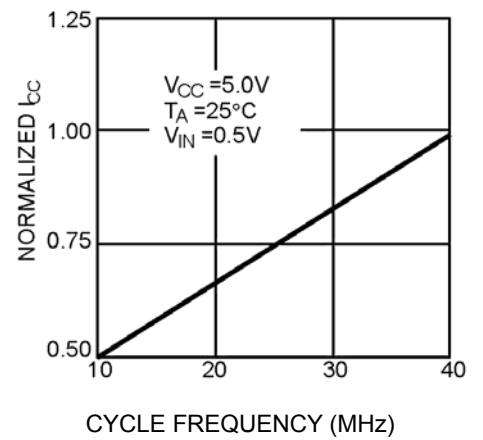


**OUTPUT SINK CURRENT
Vs. OUTPUT VOLTAGE**



**OUTPUT SOURCE CURRENT
Vs. OUTPUT VOLTAGE**



Typical DC and AC Characteristics (continued)
TYPICAL POWER-ON CURRENT
 Vs. SUPPLY VOLTAGE

TYPICAL ACCESS TIME CHANGE
 Vs. OUTPUT LOADING

NORMALIZED I_{CC} vs. CYCLE TIME

Truth Table

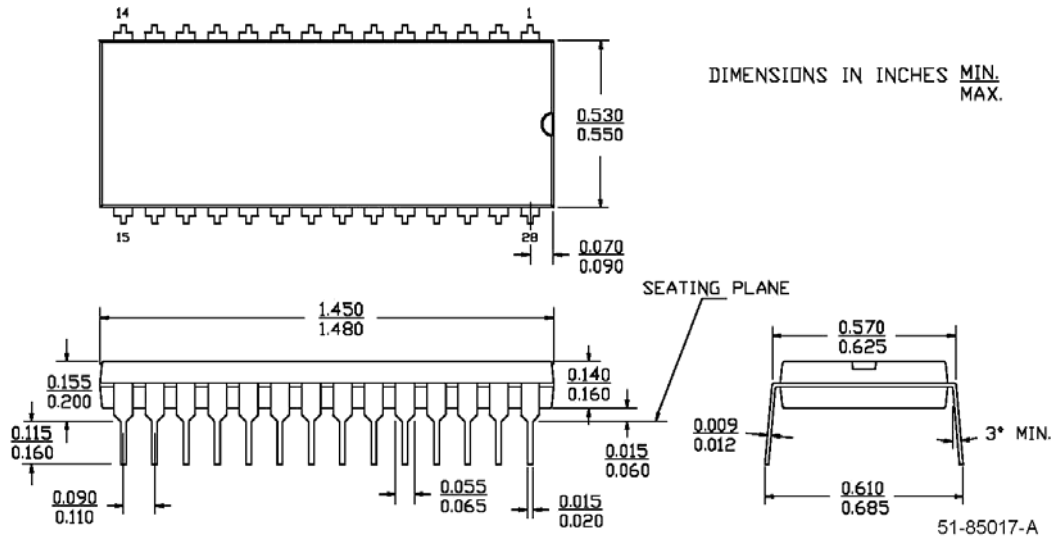
| $\overline{\text{CE}}$ | $\overline{\text{WE}}$ | $\overline{\text{OE}}$ | Inputs/Outputs | Mode | Power |
|------------------------|------------------------|------------------------|----------------|---------------------|-----------------------------|
| H | X | X | High-Z | Deselect/Power-down | Standby (I_{SB}) |
| L | H | L | Data Out | Read | Active (I_{CC}) |
| L | L | X | Data In | Write | Active (I_{CC}) |
| L | H | H | High-Z | Output Disabled | Active (I_{CC}) |

Ordering Information

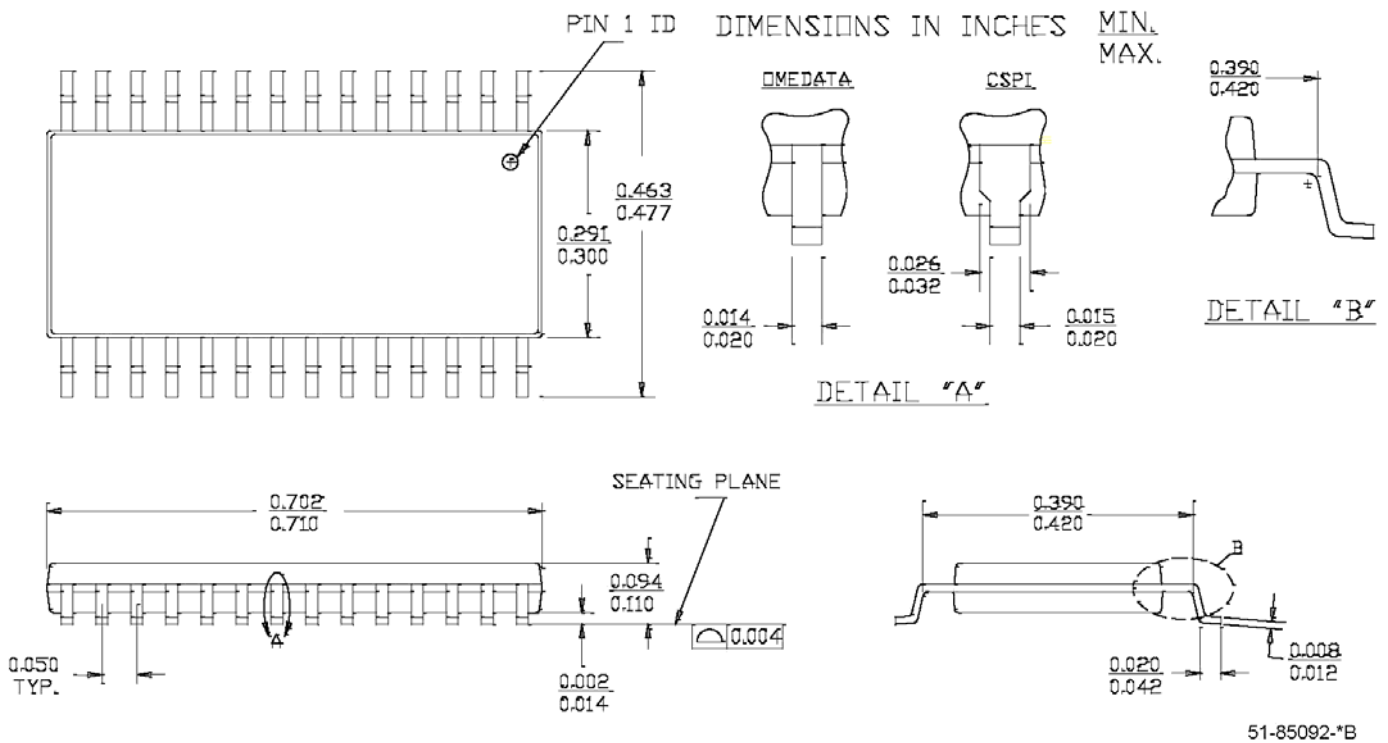
| Speed (ns) | Ordering Code | Package Name | Package Type | Operating Range |
|-----------------|-----------------|--|--|-----------------|
| 55 | CY62256LL-55SNI | SN28 | 28-lead (300-Mil Narrow Body) Narrow SOIC | Industrial |
| | CY62256LL-55ZI | Z28 | 28-lead Thin Small Outline Package | |
| | CY62256LL-55SNE | SN28 | 28-lead (300-Mil Narrow Body) Narrow SOIC | Automotive |
| | CY62256LL-55ZE | Z28 | 28-lead Thin Small Outline Package | |
| | CY62256LL-55ZRE | ZR28 | 28-lead Reverse Thin Small Outline Package | |
| 70 | CY62256-70SNC | SN28 | 28-lead (300-Mil Narrow Body) Narrow SOIC | Commercial |
| | CY62256L-70SNC | | | |
| | CY62256LL-70SNC | | | |
| | CY62256L-70SNI | | | Industrial |
| | CY62256LL-70SNI | | | |
| | CY62256LL-70ZC | Z28 | 28-lead Thin Small Outline Package | Commercial |
| | CY62256LL-70ZI | Z28 | | Industrial |
| | CY62256-70PC | P15 | 28-lead (600-Mil) Molded DIP | Commercial |
| | CY62256L-70PC | | | |
| | CY62256LL-70PC | | | |
| CY62256LL-70ZRI | ZR28 | 28-lead Reverse Thin Small Outline Package | Industrial | |

Package Diagrams

28-lead (600-mil) Molded DIP P15



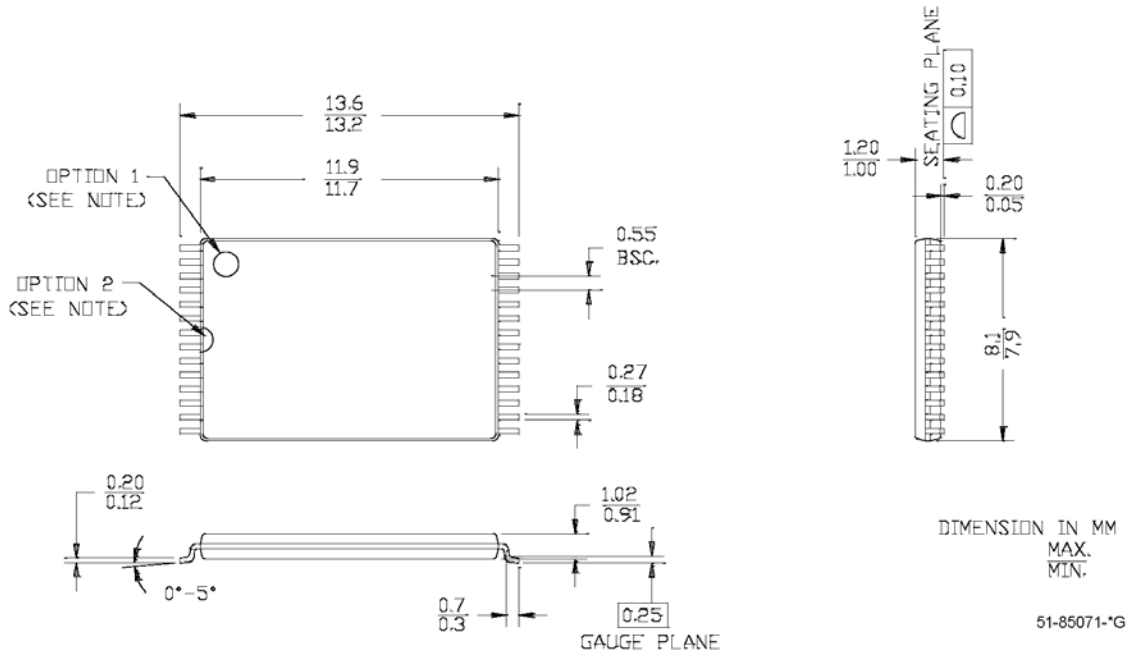
28-lead (300-mil) SNC (Narrow Body) SN28



Package Diagrams (continued)

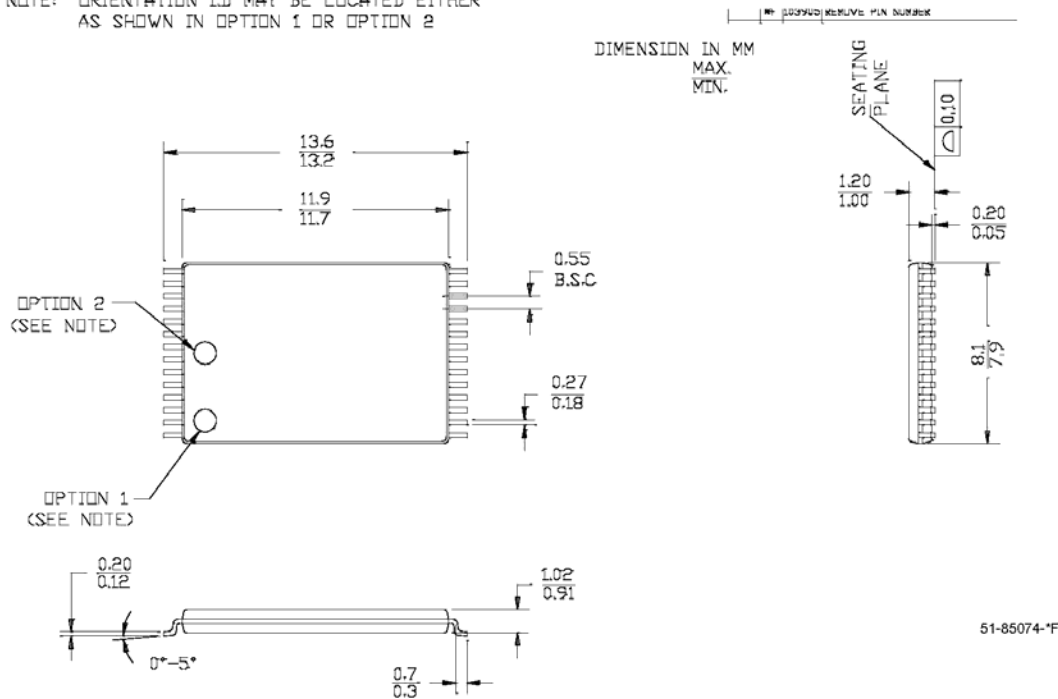
28-lead Thin Small Outline Package Type 1 (8 x 13.4 mm) Z28

NOTE: ORIENTATION ID MAY BE LOCATED EITHER AS SHOWN IN OPTION 1 OR OPTION 2



28-lead Reverse Type 1 Thin Small Outline Package (8 x 13.4 mm) ZR28

NOTE: ORIENTATION ID MAY BE LOCATED EITHER AS SHOWN IN OPTION 1 OR OPTION 2



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Document Title: CY62256 256K (32k x 8) Static RAM**Document Number: 38-05248**

| REV. | ECN NO. | Issue Date | Orig. of Change | Description of Change |
|-------------|----------------|-------------------|------------------------|---|
| ** | 113454 | 03/06/02 | MGN | Change from Spec number: 38-00455 to 38-05248 Remove obsolete parts from ordering info, standardize format |
| *A | 115227 | 05/23/02 | GBI | Changed SN Package Diagram |
| *B | 116506 | 09/04/02 | GBI | Added footnote 1. Corrected package description in Ordering information table |
| *C | 238448 | See ECN | AJU | Added Automotive product information |